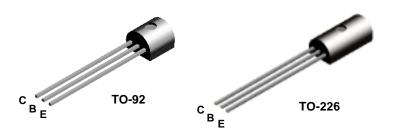
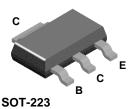


2N7051

2N7053

NZT7053





NPN Darlington Transistor

This device is designed for applications requiring extremely high gain at collector currents to 1.0 A and high breakdown voltage. Sourced from Process 06.

Absolute Maximum Ratings*

TA = 25°C unless otherwise noted

Symbol	Parameter	Value	Units
V_{CEO}	Collector-Emitter Voltage	100	V
V _{CBO}	Collector-Base Voltage	100	V
V _{EBO}	Emitter-Base Voltage	12	V
I _C	Collector Current - Continuous	1.5	Α
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

^{*}These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

- NOTES:

 1) These ratings are based on a maximum junction temperature of 150 degrees C.

 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics

TA = 25°C unless otherwise noted

Symbol	Characteristic	Max		Units	
		2N7051	2N7053	*NZT7053	
P _D	Total Device Dissipation	625	1,000	1,000	mW
	Derate above 25°C	5.0	8.0	8.0	mW/°C
$R_{\theta JC}$	Thermal Resistance, Junction to Case		50		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	200	125	125	°C/W

^{*}Device mounted on FR-4 PCB 36 mm X 18 mm X 1.5 mm; mounting pad for the collector lead min. 6 cm².

NPN Darlington Transistor

(continued)

Electrica	I Char	acteris	tics
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TA = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHAP	RACTERISTICS				
V _{(BR)CEO}	Collector-Emitter Breakdown Voltage*	$I_C = 1.0 \text{ mA}, I_B = 0$	100		V
V _{(BR)CBO}	Collector-Base Breakdown Voltage	$I_C = 100 \mu A, I_E = 0$	100		V
V _{(BR)EBO}	Emitter-Base Breakdown Voltage	$I_E = 1.0 \text{ mA}, I_C = 0$	12		V
I _{CBO}	Collector-Cutoff Current	$V_{CB} = 80 \text{ V}, I_{E} = 0$		0.1	μΑ
I _{CES}	Collector-Cutoff Current	$V_{CE} = 80 \text{ V}, I_{E} = 0$		0.2	μΑ
I _{EBO}	Emitter-Cutoff Current	$V_{EB} = 7.0 \text{ V}, I_{C} = 0$		0.1	μΑ

ON CHARACTERISTICS*

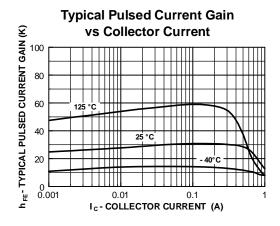
h _{FE}	DC Current Gain	$I_C = 100 \text{ mA}, V_{CE} = 5.0 \text{ V}$	10,000		
		$I_C = 1.0 \text{ A}, V_{CE} = 5.0 \text{ V}$	1,000	20,000	
V _{CE(sat)}	Collector-Emitter Saturation Voltage	$I_C = 100 \text{ mA}, I_B = 0.1 \text{ mA}$		1.5	V
V _{BE(on)}	Base-Emitter On Voltage	$I_C = 100 \text{ mA}, V_{BE} = 5.0 \text{ V}$		2.0	V

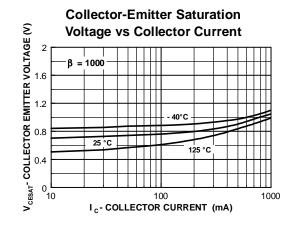
SMALL SIGNAL CHARACTERISTICS

F _T	Transition Frequency	$I_C = 100 \text{ mA}, V_{CE} = 5.0 \text{ V}$	200		MHz
C _{cb}	Collector-Base Capacitance	V _{CB} = 10 V,f= 1.0 MHz 2N7053		8.0	pF
h _{fe}	Small-Signal Current Gain	$V_{CE} = 5.0 \text{ V}, I_{C} = 100 \text{ mA},$ f = 20 MHz	10	100	

^{*}Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 1.0%

Typical Characteristics

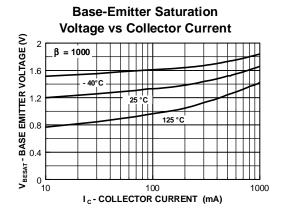


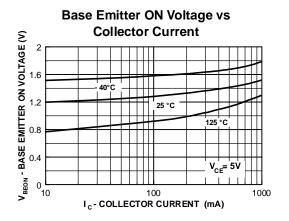


NPN Darlington Transistor

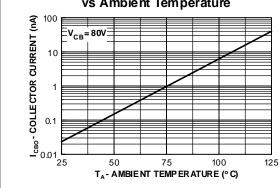
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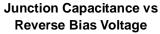
Typical Characteristics (continued)

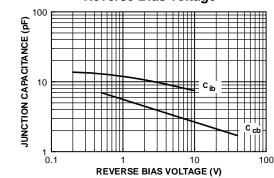




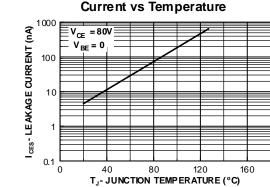
Collector-Cutoff Current vs Ambient Temperature



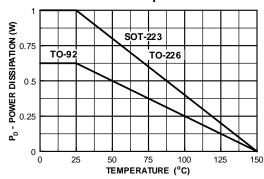




Typical Collector-Emitter Leakage Current vs Temperature



Power Dissipation vs Ambient Temperature



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